



## FAST CMOS 20-BIT BUFFER

**IDT54/74FCT162827AT/BT/CT/ET**

### FEATURES:

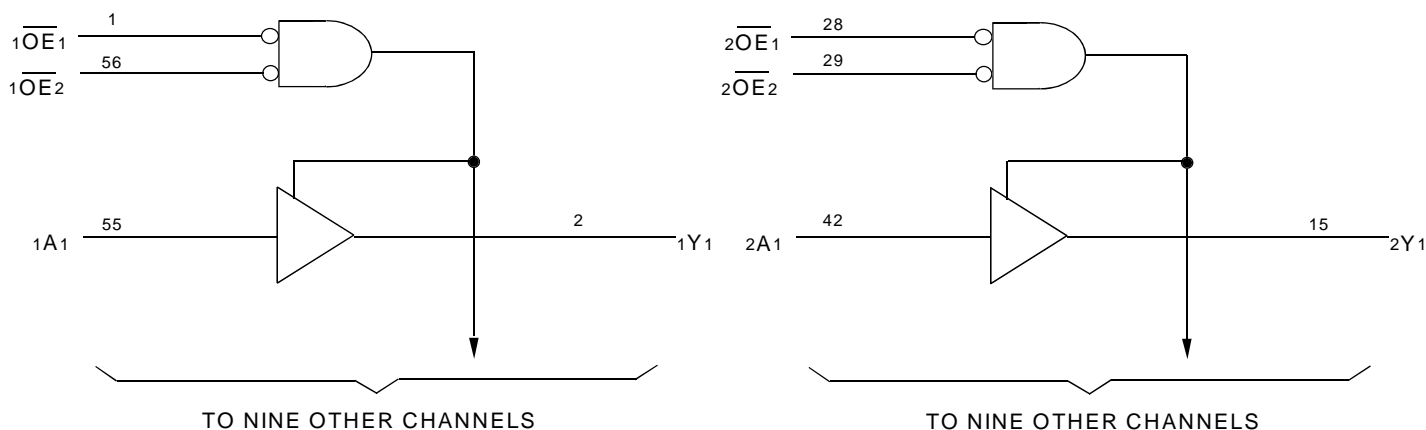
- 0.5 MICRON CMOS Technology
- High-speed, low-power CMOS replacement for ABT functions
- Typical  $t_{sk(o)}$  (Output Skew) < 250ps
- Low input and output leakage  $\leq 1\mu A$  (max.)
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- 25 mil pitch SSOP, 19.6 mil pitch TSSOP, 15.7 mil pitch TVSOP and 25 mil pitch CERPACK packages
- Extended commercial range of  $-40^{\circ}C$  to  $+85^{\circ}C$
- $V_{CC} = 5V \pm 10\%$
- Balanced Output Drivers:
  - $\pm 24mA$  (commercial)
  - $\pm 16mA$  (military)
- Reduced system switching noise
- Typical VOLP (Output Ground Bounce) < 0.6V at  $V_{CC} = 5V, T_A = 25^{\circ}C$

### DESCRIPTION:

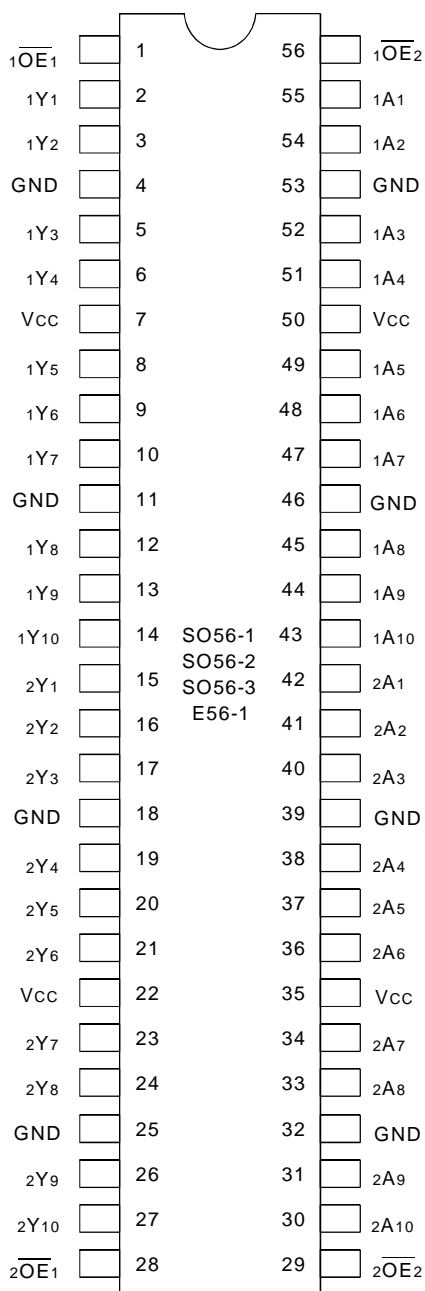
The FCT162827AT/BT/CT/ET 20-bit buffers are built using advanced dual metal CMOS technology. These 20-bit bus drivers provide high-performance bus interface buffering for wide data/address paths or buses carrying parity. Two pair of NAND-ed output enable controls offer maximum control flexibility and are organized to operate the device as two 10-bit buffers or one 20-bit buffer. Flow-through organization of signal pins simplifies layout. All inputs are designed with hysteresis for improved noise margin.

The FCT162827AT/BT/CT/ET has balanced output drive with current limiting resistors. This offers low ground bounce, minimal undershoot, and controlled output fall times—reducing the need for external series terminating resistors. The FCT162827AT/BT/CT/ET are plug-in replacements for the FCT16827AT/BT/CT/ET and ABT16827 for on-board interface applications.

### FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



SSOP/TSSOP/TVSOP/CERPACK  
TOP VIEW

## ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Description	Max	Unit
$V_{TERM}^{(2)}$	Terminal Voltage with Respect to GND	-0.5 to +7	V
$V_{TERM}^{(3)}$	Terminal Voltage with Respect to GND	-0.5 to $V_{CC}+0.5$	V
TSTG	Storage Temperature	-65 to +150	°C
I <sub>OUT</sub>	DC Output Current	-60 to +120	mA

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### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- All device terminals except FCT162XXXXT Output and I/O terminals.
- Output and I/O terminals for FCT162XXXXT.

## CAPACITANCE ( $T_A = +25^\circ\text{C}$ , $f = 1.0\text{MHz}$ )

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$V_{IN} = 0\text{V}$	3.5	6	pF
C <sub>OUT</sub>	Output Capacitance	$V_{OUT} = 0\text{V}$	3.5	8	pF

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### NOTE:

- This parameter is measured at characterization but not tested.

## PIN DESCRIPTION

Pin Names	Description
$\overline{xOE_x}$	Output Enable Inputs (Active LOW)
$xAX$	Data Inputs
$xYx$	3-State Outputs

## FUNCTION TABLE(1)

Inputs			Outputs
$\overline{xOE_1}$	$\overline{xOE_2}$	$xAX$	$xYx$
L	L	L	L
L	L	H	H
H	X	X	Z
X	H	X	Z

### NOTE:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care  
Z = High-Impedance

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ ; Military:  $T_A = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$V_{IH}$	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
$V_{IL}$	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
$I_{IH}$	Input HIGH Current (Input pins) <sup>(5)</sup>	$V_{CC} = \text{Max.}$	$V_I = V_{CC}$	—	—	$\pm 1$	$\mu\text{A}$
	Input HIGH Current (I/O pins) <sup>(5)</sup>			—	—	$\pm 1$	
$I_{IL}$	Input LOW Current (Input pins) <sup>(5)</sup>		$V_I = \text{GND}$	—	—	$\pm 1$	
	Input LOW Current (I/O pins) <sup>(5)</sup>			—	—	$\pm 1$	
$I_{OZH}$	High Impedance Output Current	$V_{CC} = \text{Max.}$	$V_O = 2.7\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{OZL}$	(3-State Output pins) <sup>(5)</sup>		$V_O = 0.5\text{V}$	—	—	$\pm 1$	
$V_{IK}$	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$		—	-0.7	-1.2	V
$I_{OS}$	Short Circuit Current	$V_{CC} = \text{Max.}, V_O = \text{GND}^{(3)}$		-80	-140	-250	mA
$V_H$	Input Hysteresis	—		—	100	—	mV
$I_{CCL}$ $I_{CCH}$ $I_{CCZ}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ $V_{IN} = \text{GND or } V_{CC}$		—	5	500	$\mu\text{A}$

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## OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$I_{ODL}$	Output LOW Current	$V_{CC} = 5\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_O = 1.5\text{V}^{(3)}$		60	115	200	mA
$I_{ODH}$	Output HIGH Current	$V_{CC} = 5\text{V}, V_{IN} = V_{IH} \text{ or } V_{IL}, V_O = 1.5\text{V}^{(3)}$		-60	-115	-200	mA
$V_{OH}$	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -16\text{mA MIL.}$ $I_{OH} = -24\text{mA COM'L.}$	2.4	3.3	—	V
$V_{OL}$	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 16\text{mA MIL.}$ $I_{OL} = 24\text{mA COM'L.}$	—	0.3	0.55	V

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### NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at  $V_{CC} = 5.0\text{V}$ ,  $+25^{\circ}\text{C}$  ambient.
- Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
- Duration of the condition can not exceed one second.
- The test limit for this parameter is  $\pm 5\mu\text{A}$  at  $T_A = -55^{\circ}\text{C}$ .

## POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$\Delta I_{CC}$	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	1.5	mA
$I_{CCD}$	Dynamic Power Supply Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$ Outputs Open $\overline{xOE}_1 = \overline{xOE}_2 = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	60	100	$\mu A/\text{MHz}$
$I_C$	Total Power Supply Current <sup>(6)</sup>	$V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ 50% Duty Cycle $\overline{xOE}_1 = \overline{xOE}_2 = \text{GND}$ One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.6	1.5	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	0.9	2.3	
		$V_{CC} = \text{Max.}$ Outputs Open $f_i = 2.5\text{MHz}$ 50% Duty Cycle $\overline{xOE}_1 = \overline{xOE}_2 = \text{GND}$ Twenty Bits Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	3	5.5 <sup>(5)</sup>	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	8	20.5 <sup>(5)</sup>	

### NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at  $V_{CC} = 5.0V$ ,  $+25^\circ\text{C}$  ambient.
- Per TTL driven input ( $V_{IN} = 3.4V$ ). All other inputs at  $V_{CC}$  or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$   
 $I_C = I_{CC} + \Delta I_{CC} D_{HNT} + I_{CCD} (f_{CP} N_{CP}/2 + f_i N_i)$   
 $I_{CC} = \text{Quiescent Current (} I_{CCL}, I_{CCH} \text{ and } I_{CCZ})$   
 $\Delta I_{CC} = \text{Power Supply Current for a TTL High Input (} V_{IN} = 3.4V)$   
 $D_H = \text{Duty Cycle for TTL Inputs High}$   
 $N_T = \text{Number of TTL Inputs at } D_H$   
 $I_{CCD} = \text{Dynamic Current Caused by an Input Transition Pair (HLH or LHL)}$   
 $f_{CP} = \text{Clock Frequency for Register Devices (Zero for Non-Register Devices)}$   
 $N_{CP} = \text{Number of Clock Inputs at } f_{CP}$   
 $f_i = \text{Input Frequency}$   
 $N_i = \text{Number of Inputs at } f_i$

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Symbol	Parameter	Condition <sup>(1)</sup>	FCT162827AT				FCT162827BT				Unit
			Com'l.		Mil.		Com'l.		Mil.		
			Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	
tPLH tPHL	Propagation Delay xAX to xYx	CL = 50pF RL = 500Ω	1.5	8	1.5	9	1.5	5	1.5	6.5	ns
		CL = 300pF <sup>(4)</sup> RL = 500Ω	1.5	15	1.5	17	1.5	13	1.5	14	
tPZH tPZL	Output Enable Time xOĒx to xYx	CL = 50pF RL = 500Ω	1.5	12	1.5	13	1.5	8	1.5	9	ns
		CL = 300pF <sup>(4)</sup> RL = 500Ω	1.5	23	1.5	25	1.5	15	1.5	16	
tPHZ tPLZ	Output Disable Time xOĒx to xYx	CL = 5pF <sup>(4)</sup> RL = 500Ω	1.5	9	1.5	9	1.5	6	1.5	7	ns
		CL = 50pF RL = 500Ω	1.5	10	1.5	10	1.5	7	1.5	8	
tsk(o)	Output Skew <sup>(3)</sup>		—	0.5	—	0.5	—	0.5	—	0.5	ns

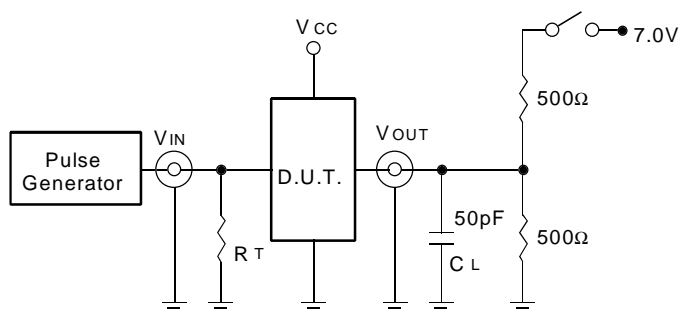
Symbol	Parameter	Condition <sup>(1)</sup>	FCT162827CT				FCT162827ET				Unit
			Com'l.		Mil.		Com'l.		Mil.		
			Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	
tPLH tPHL	Propagation Delay xAX to xYx	CL = 50pF RL = 500Ω	1.5	4.4	1.5	5	1.5	3.2	—	—	ns
		CL = 300pF <sup>(4)</sup> RL = 500Ω	1.5	10	1.5	11	1.5	7	—	—	
tPZH tPZL	Output Enable Time xOĒx to xYx	CL = 50pF RL = 500Ω	1.5	7	1.5	8	1.5	4.8	—	—	ns
		CL = 300pF <sup>(4)</sup> RL = 500Ω	1.5	14	1.5	15	1.5	9	—	—	
tPHZ tPLZ	Output Disable Time xOĒx to xYx	CL = 5pF <sup>(4)</sup> RL = 500Ω	1.5	5.7	1.5	6.7	1.5	4	—	—	ns
		CL = 50pF RL = 500Ω	1.5	6	1.5	7	1.5	4	—	—	
tsk(o)	Output Skew <sup>(3)</sup>		—	0.5	—	0.5	—	0.5	—	—	ns

### NOTES:

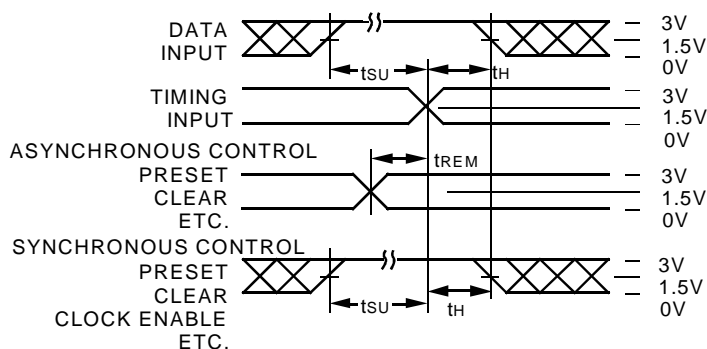
1. See test circuit and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.
4. This condition is guaranteed but not tested.

## TEST CIRCUITS AND WAVEFORMS

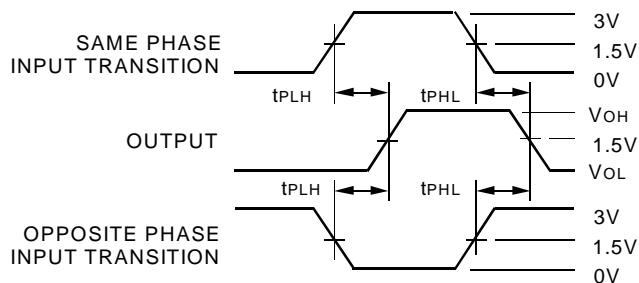
### TEST CIRCUITS FOR ALL OUTPUTS



### SET-UP, HOLD, AND RELEASE TIMES



### PROPAGATION DELAY



### SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

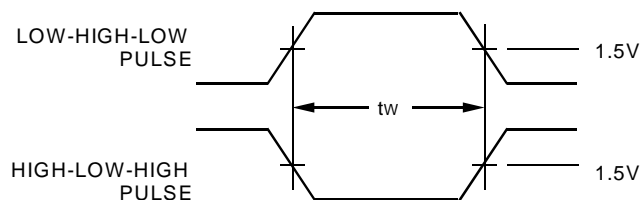
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#### DEFINITIONS:

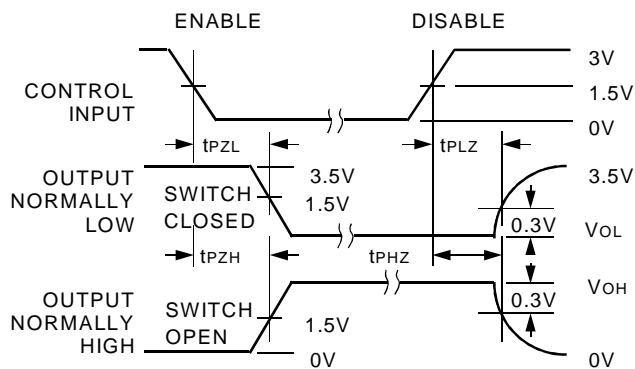
$C_L$  = Load capacitance: includes jig and probe capacitance.

$R_T$  = Termination resistance: should be equal to  $Z_{OUT}$  of the Pulse Generator.

### PULSE WIDTH



### ENABLE AND DISABLE TIMES



#### NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- Pulse Generator for All Pulses: Rate  $\leq 1.0\text{MHz}$ ;  $t_F \leq 2.5\text{ns}$ ;  $t_R \leq 2.5\text{ns}$ .

## ORDERING INFORMATION

IDT	XX	FCT	XXX	XXXX	X	X	
	Temp. Range		Family	Device Type	Package	Process	
							Blank B
							Commercial MIL-STD-883, Class B
							PV
							Shrink Small Outline Package (SO56-1)
							PA
							Thin Shrink Small Outline Package (SO56-2)
							PF
							Thin Very Small Outline Package (SO56-3)
							E
							CERPACK (E56-1)
							827AT
							20-Bit Buffer
							827BT
							827CT
							827ET
							162
							Double-Density 5 Volt Balanced Drive
							54
							– 55°C to +125°C
							74
							– 40°C to +85°C



### CORPORATE HEADQUARTERS

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